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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF:

Keiichi KUSHIDA, et al.

SERIAL NO: 10/828,282

GROUP: 2117

FILED: April 21, 2004

EXAMINER: Cynthia H. BRITT

RCE FILED: December 12, 2007

FOR: SEMICONDUCTOR DEVICE WITH MEMORY AND METHOD FOR  
MEMORY TEST

**LETTER**


Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Submitted herewith is a Chinese Office Action (with English Translation) for the Examiner's consideration. The reference(s) listed therein have been cited in the Office Action dated January 17, 2007.

Respectfully Submitted,

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